EXAS RUMENTS Data sheet acquired from Harris Semiconductor SCHS104C - Revised October 2003

CMOS Hex 'D'-Type Flip-Flop

High-Voltage Types (20-Volt Rating)

CD40174B consists of six identical 'D'-type flip-flops having independent DATA inputs. The CLOCK and CLEAR inputs are common to all six units. Data is transferred to the Q outputs on the positive-going transition of the clock pulse. All six flip-flops are simultaneously reset by a low level on the CLEAR input.

The CD40174B types are supplied in 16-lead hermetic dual-in-line ceramic packages (F3A suffix), 16-lead dual-in-line plastic packages (E suffix), 16-lead small-outline packages (M, M96, MT, and NSR suffixes), and 16-lead thin shrink small-outline packages (PW and PWR suffixes).

MAXIMUM RATINGS, Absolute-Maximum Values:

DC SUPPLY-VOLTAGE RANGE, (VDD)
Voltages referenced to V _{SS} Terminal)
INPUT VOLTAGE RANGE, ALL INPUTS
DC INPUT CURRENT, ANY ONE INPUT ±10mA
POWER DISSIPATION PER PACKAGE (PD):
For $T_A = -55^{\circ}C$ to $+100^{\circ}C$
For T _A = +100°C to +125°C Derate Linearity at 12mW/°C to 200mW
DEVICE DISSIPATION PER OUTPUT TRANSISTOR
FOR T _A = FULL PACKAGE-TEMPERATURE RANGE (All Package Types)
OPERATING-TEMPERATURE RANGE (T _A)
STORAGE TEMPERATURE RANGE (Tsta)

STORAGE LEAR ENAN	She holde (i sig)	
LEAD TEMPERATURE	(DURING SOLDERING):	

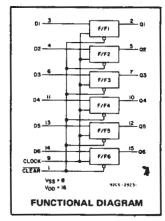
At distance 1/16 ± 1/32 inch (1.59 ± 0.79mm) from case for 10s max +265°C

Features:

- = 5-V, 10-V, and 15-V parametric rating
- Standardized symmetrical output characteristics
- = 100% tested for quiescent current at 20 V
- Maximum input current of 1 µA at 18 V
- over full package-temperature range; 100 nA at 18 V and 25°C
- Noise margin (over full package-temperature range): 1 V at V_{DD} = 5 V 2 V at V_{DD} = 10 V 2.5 V at V_{DD} = 15 V

- Meets all requirements of JEDEC Tentative Standard No. 13A, "Standard Specifications for Description of 'B' Series CMOS Devices"

CD40174B Types



Applications:

- Shift Registers
- Buffer/Storage Registers
- Pattern Generators

TRUTH TABLE FOR 1 OF 6 FLIP-FLOPS

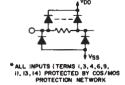
	OUTPUT		
CLOCK	DATA	CLEAR	٥
	0	1	0
	1	1	1
2	×	1	NC
X	×	0	0

1 = High Level 0 = Low Level

-09 10.12.15)

9205-2983

X = Don't Care NC = No Change





CL

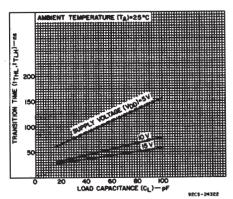
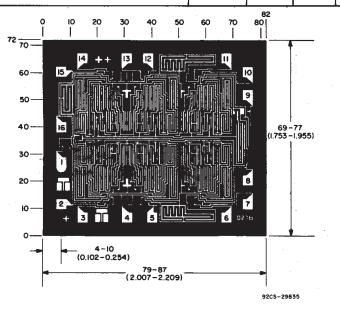
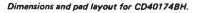


Fig. 2- Typical transition time as a function of load capacitance.

RECOMMENDED OPERATING CONDITIONS at $T_A = 25^{\circ}C$, Except as Noted. For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	V _{DD}	LIN	UNITS	
	(V)	Min.	Max.	1
Supply-Voltage Range (For T _A = Full Package-			40	
Temperature Range)		3	18	V
	5	40	-	
Data Setup Time, t _{SU}	10	20	- 1	ns
	15	10	-	
	5	80	-	
Data Hold Time, t _H	10	40	-	ns
	15	30	-	
	5		3.5	1
Clock Input Frequency, f _{CL}	10	dc	6	MHz
	15		8	
	5	· _	15	
Clock Input Rise or Fall Time, trCL, trCL	10	. –	15	μs
	15	-	15	
	5	130	- 1	
Clock Input Pulse Width, tWL, tWH	10	60	-	ns
	15	40	- 1	
**************************************	5	100	-	
Clear Pulse Width, twL	10	50	-	ns
•••	15	40	-	
	5	0	-	
Clear Removal Time, tREM	10	0	-	ns
	15	0	· · ·	





Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10^{-3} inch) .

The photographs and dimensions of each CMOS chip represent a chip when it is part of the wefer. When the wafer is separated into individual chips, the angle of cleavage may vary with respect to the chip face for different chips. The actual dimensions of the isolated chip, therefore, may differ slightly from the nominal dimensions shown. The user should consider a tolerance of -3 mils 10 +16 mila applicable to the nominal dimensions shown.

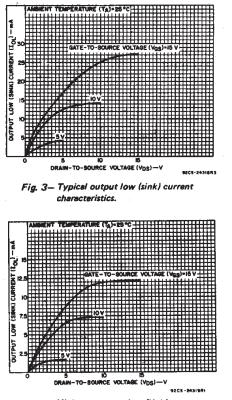
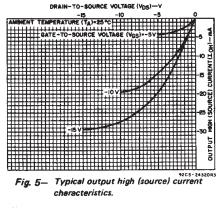
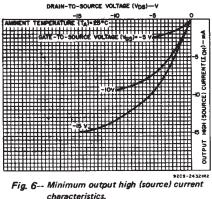


Fig. 4— Minimum output low (sink) current characteristics.

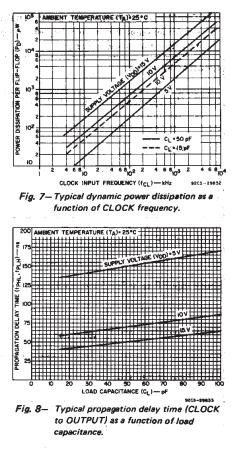


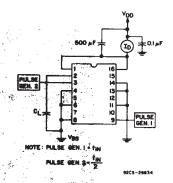


3

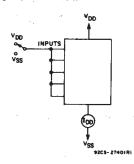
STATIC ELECTRICAL CHARACTERISTICS

CHARAC-	CONI	οιτιο	NS	LIMITS AT INDICATED TEMPERATURES (°C)							U N
TERISTIC	Vo	VIN	V _{DD}				a cert		+25		Ι ΄
	(V)	(V)	(V)-	-55	40	+85	+125	Min.	Тур.	Max.	S
Quiescent	_	0,5	5	1	1	30	30	-	0.02	1	
Device	· _	0,10	10	2	2	60	60	-	0.02	2]μ/
Current, fDD		0,15	15	4	4	120	120	-	0.02	4	
Max.	n i n	0,20	20	20	20	600	600	-	0.04	20]
Output Low (Sink)	0.4	0,5	5	0.64	0.61	0.42	0.36	0.51	1	-	
Current	0.5	0,10	10	1.6	1.5	1.1	0.9	1.3	2.6	-]
I _{OL} Min.	1.5	0,15	15	4.2	4	2.8	2.4	3.4	6.8	-	
Output High	4.6	0,5	5	0.64	-0.61	-0.42	-0.36	-0.51	-1]_m/
(Source)	2.5	0,5	5	-2	-1.8	-1.3	-1.15	-1.6	-3.2	-]
Current,	9.5	0,10	10	-1.6	-1.5	-1.1	-0.9	-1.3	2.6		
IOH Min.	13.5	0,15	15	-4.2	-4	-2.8	-2.4	-3.4	6.8		1
Output Voltage:	- <u>-</u> 1	0,5	5		0	.05	_	0	0.05		
Low-Level,	 , :	0,10	10		0	.05			3	0.05]
V _{OL} Max.	. 	0,15	15		0	.05		<u> </u>	0	0.05],
Output Voltage:	— · :	0,5	5		4	.95		4.95	5	_	ľ
High-Level,	-	0,10	10		9	.95		9,95	10]
V _{OH} Min.	-	0,15	15		14	.95		14.95	15	-	
Input Low	0.5,4.5	1	5		1	.5			-	1.5	
Voltage,	1,9	_	10			3		_	-	3	
VIL Max.	1.5,13.5		15			4		-	-	4],
Inpuț High	0.5,4.5	_	5.			8.5		3.5			
Voltage,	1,9		10		7 7				·		
V _{IH} Min.	1.5,13.5	-	15			11		11	-	² –	
Input Current † _{IN} Max.		0,18	18	±0.1	±0.1	±1	±1	- :	±10 ⁻⁵	±0.1	μA





Dynamic power dissipation test circuit. 當



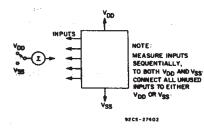
1, CL 'DD CLOCK 10% /00 DATA INPUT - 50% SULLH)* SUGHL TTLH THU /D0 90% OUTPUT -10 % *PLH - 1PHL *(LH) OR (HL) OPTIONAL REN CLEAR -50% 9203-2006984

Fig. 10- Definition of setup, hold, propagation delay, and removal times.

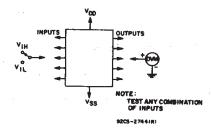
Fig. 11 - Quiescent device current test circuit.

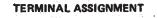
CHARACTERISTIC		TEST CONDITIONS		LIMITS		UNITS
		V _{DD} (V)	Min.	Тур.	Max.	
Proposition Dalay Tim	- (5		150	300	
Propagation Delay Tim		10	_	70	140	ns .
Clock to Output,	^t PHL ^{, t} PLH	15	_	50	100	
		5	-	100	200	<i>,</i> '
Clear to Output,	^t PHL	10	-	50	100	ns
		15	_	40	80	1
		5		100	200	
Transition Time,	^t THL ^{, t} TLH	10	-	50	100	ns
		15	_	40	80	
Minimum Pulse Width.		5	_	65	130	
Clock,		10	_	30	60	ns
CIOCK,	^t WL ^{, t} WH	15	_	20	40	
	÷ 1.	5		50	100	
Clear,	twl	10	· · _	25	50	ns
		15	_	20	40	
	5		20	40		
Minimum Data Setup T	ime, t _{SU}	10	-	10	20	ns
	00	15	-	0	10	
		5	_	40	80	
Minimum Data Hold Ti	me, t _H	10	-	20	40	ns
	••	15	-	15	30	
	····	5	3.5	7	_	
Maximum Clock Frequ	ency, f _{CI}	10	6	12		MHz
·	UL	15	- 8	16		
		5 and 5	15	3 <u> </u>	1-1-1	
Maximum Clock Rise o	r Fall	10	15	· – .	- 1	μs
Time, t _r CL, t _f CL		15	15	- **	<u> </u>	
Input Capacitance, CIN	4					
Clear		-	_	25	40	pF
All other		-	_	5	7.5]
Minimum Clear Remov		5	_	-40	0	
Time,		10		15	o	ns
1 ((11 0 ,	tREM	15	_	-10	0	

DYNAMIC ELECTRICAL CHARACTERISTICS at $T_A = 25^{\circ}C$; Input t_p , $t_f = 20$ ns, $C_L = 50$ pF, $R_L = 200$ k Ω



an in the second se





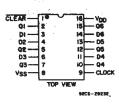




Fig. 13 - Input voltage test circuit.



24-Aug-2014

PACKAGING INFORMATION

Orderable Device	Status	Package Type	-	Pins	-	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
CD40174BE	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD40174BE	Samples
CD40174BEE4	ACTIVE	PDIP	Ν	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD40174BE	Samples
CD40174BF	ACTIVE	CDIP	J	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	CD40174BF	Samples
CD40174BF3A	ACTIVE	CDIP	J	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	CD40174BF3A	Samples
CD40174BM	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD40174BM	Samples
CD40174BM96	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD40174BM	Samples
CD40174BNSR	ACTIVE	SO	NS	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD40174B	Samples
CD40174BPW	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CM0174B	Samples
CD40174BPWE4	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CM0174B	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.



www.ti.com

24-Aug-2014

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

⁽⁵⁾ Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

⁽⁶⁾ Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF CD40174B, CD40174B-MIL :

- Catalog: CD40174B
- Military: CD40174B-MIL

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Military QML certified for Military and Defense Applications

PACKAGE MATERIALS INFORMATION

www.ti.com

TAPE AND REEL INFORMATION

REEL DIMENSIONS

TEXAS INSTRUMENTS





TAPE AND REEL INFORMATION

TAPE DIMENSIONS



A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

*	All dimensions are nominal												
	Device		Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
	CD40174BM96	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
	CD40174BNSR	SO	NS	16	2000	330.0	16.4	8.2	10.5	2.5	12.0	16.0	Q1

TEXAS INSTRUMENTS

www.ti.com

PACKAGE MATERIALS INFORMATION

14-Jul-2012



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CD40174BM96	SOIC	D	16	2500	333.2	345.9	28.6
CD40174BNSR	SO	NS	16	2000	367.0	367.0	38.0

J (R-GDIP-T**) 14 LEADS SHOWN

CERAMIC DUAL IN-LINE PACKAGE



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. This package is hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



NOTES:

- A. All linear dimensions are in inches (millimeters).B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- \triangle The 20 pin end lead shoulder width is a vendor option, either half or full width.



D (R-PDSO-G16)

PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AC.



4211283-4/E 08/12

D (R-PDSO-G16) PLASTIC SMALL OUTLINE Stencil Openings (Note D) Example Board Layout (Note C) –16x0,55 -14x1,27 -14x1,27 16x1,50 5,40 5.40 Example Non Soldermask Defined Pad Example Pad Geometry (See Note C) 0,60 .55 Example 1. Solder Mask Opening (See Note E) -0,07 All Around

NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
 E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



PW (R-PDSO-G16)

PLASTIC SMALL OUTLINE



NOTES:

A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994. β . This drawing is subject to change without notice.

Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.

Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.

E. Falls within JEDEC MO-153





NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



MECHANICAL DATA

PLASTIC SMALL-OUTLINE PACKAGE

0,51 0,35 ⊕0,25⊛ 1,27 8 14 0,15 NOM 5,60 8,20 5,00 7,40 \bigcirc Gage Plane ₽ 0,25 7 1 1,05 0,55 0-10 Δ 0,15 0,05 Seating Plane — 2,00 MAX 0,10PINS ** 14 16 20 24 DIM 10,50 10,50 12,90 15,30 A MAX A MIN 9,90 9,90 12,30 14,70 4040062/C 03/03

NOTES: A. All linear dimensions are in millimeters.

NS (R-PDSO-G**)

14-PINS SHOWN

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15.



IMPORTANT NOTICE

Texas Instruments Incorporated and its subsidiaries (TI) reserve the right to make corrections, enhancements, improvements and other changes to its semiconductor products and services per JESD46, latest issue, and to discontinue any product or service per JESD48, latest issue. Buyers should obtain the latest relevant information before placing orders and should verify that such information is current and complete. All semiconductor products (also referred to herein as "components") are sold subject to TI's terms and conditions of sale supplied at the time of order acknowledgment.

TI warrants performance of its components to the specifications applicable at the time of sale, in accordance with the warranty in TI's terms and conditions of sale of semiconductor products. Testing and other quality control techniques are used to the extent TI deems necessary to support this warranty. Except where mandated by applicable law, testing of all parameters of each component is not necessarily performed.

TI assumes no liability for applications assistance or the design of Buyers' products. Buyers are responsible for their products and applications using TI components. To minimize the risks associated with Buyers' products and applications, Buyers should provide adequate design and operating safeguards.

TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right relating to any combination, machine, or process in which TI components or services are used. Information published by TI regarding third-party products or services does not constitute a license to use such products or services or a warranty or endorsement thereof. Use of such information may require a license from a third party under the patents or other intellectual property of the third party, or a license from TI under the patents or other intellectual property of TI.

Reproduction of significant portions of TI information in TI data books or data sheets is permissible only if reproduction is without alteration and is accompanied by all associated warranties, conditions, limitations, and notices. TI is not responsible or liable for such altered documentation. Information of third parties may be subject to additional restrictions.

Resale of TI components or services with statements different from or beyond the parameters stated by TI for that component or service voids all express and any implied warranties for the associated TI component or service and is an unfair and deceptive business practice. TI is not responsible or liable for any such statements.

Buyer acknowledges and agrees that it is solely responsible for compliance with all legal, regulatory and safety-related requirements concerning its products, and any use of TI components in its applications, notwithstanding any applications-related information or support that may be provided by TI. Buyer represents and agrees that it has all the necessary expertise to create and implement safeguards which anticipate dangerous consequences of failures, monitor failures and their consequences, lessen the likelihood of failures that might cause harm and take appropriate remedial actions. Buyer will fully indemnify TI and its representatives against any damages arising out of the use of any TI components in safety-critical applications.

In some cases, TI components may be promoted specifically to facilitate safety-related applications. With such components, TI's goal is to help enable customers to design and create their own end-product solutions that meet applicable functional safety standards and requirements. Nonetheless, such components are subject to these terms.

No TI components are authorized for use in FDA Class III (or similar life-critical medical equipment) unless authorized officers of the parties have executed a special agreement specifically governing such use.

Only those TI components which TI has specifically designated as military grade or "enhanced plastic" are designed and intended for use in military/aerospace applications or environments. Buyer acknowledges and agrees that any military or aerospace use of TI components which have *not* been so designated is solely at the Buyer's risk, and that Buyer is solely responsible for compliance with all legal and regulatory requirements in connection with such use.

TI has specifically designated certain components as meeting ISO/TS16949 requirements, mainly for automotive use. In any case of use of non-designated products, TI will not be responsible for any failure to meet ISO/TS16949.

Products		Applications	
Audio	www.ti.com/audio	Automotive and Transportation	www.ti.com/automotive
Amplifiers	amplifier.ti.com	Communications and Telecom	www.ti.com/communications
Data Converters	dataconverter.ti.com	Computers and Peripherals	www.ti.com/computers
DLP® Products	www.dlp.com	Consumer Electronics	www.ti.com/consumer-apps
DSP	dsp.ti.com	Energy and Lighting	www.ti.com/energy
Clocks and Timers	www.ti.com/clocks	Industrial	www.ti.com/industrial
Interface	interface.ti.com	Medical	www.ti.com/medical
Logic	logic.ti.com	Security	www.ti.com/security
Power Mgmt	power.ti.com	Space, Avionics and Defense	www.ti.com/space-avionics-defense
Microcontrollers	microcontroller.ti.com	Video and Imaging	www.ti.com/video
RFID	www.ti-rfid.com		
OMAP Applications Processors	www.ti.com/omap	TI E2E Community	e2e.ti.com
Wireless Connectivity	www.ti.com/wirelessconne	ctivity	

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2016, Texas Instruments Incorporated